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Form PTO-1449 (modified) List of Patents and Publications For Applicant's Information Disclosure Statement (Use several sheets if necessary)	ATTY. DKT. NO. 5589-04101 APPLICANT: Stokowski et al. FILING DATE: October 6, 2003	SERIAL NO. 10/679,617 GROUP: 2877

U.S. PATENT DOCUMENTS

EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
		6466315	10/2002	Karpol et al.			
		6268093	07/2001	Kenan et al.			
		6184976	02/2001	Park et al.			
		6691052	02/2004	Maurer			

U.S. PATENT APPLICATION DOCUMENTS

EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
		2003/0207475	11/2003	Nakasuji et al.			

FOREIGN PATENT DOCUMENTS

EXAM. INITIALS	REF. DES.	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	E1	Barty et al., "Aerial Image Microscopes for the inspection of defects in EUV masks," Proceedings of SPIE, Vol. 4889, 2002, pp. 1073-1084.
	E2	Yan et al., "Printability of Pellicle Defects in DUV 0.5 μm Lithography," SPIE Vol. 1604, 1991, pp. 106-117.

EXAMINER: /Gregory Toatley/ DATE CONSIDERED: 04/24/2008

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the patent owner.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /G.T./